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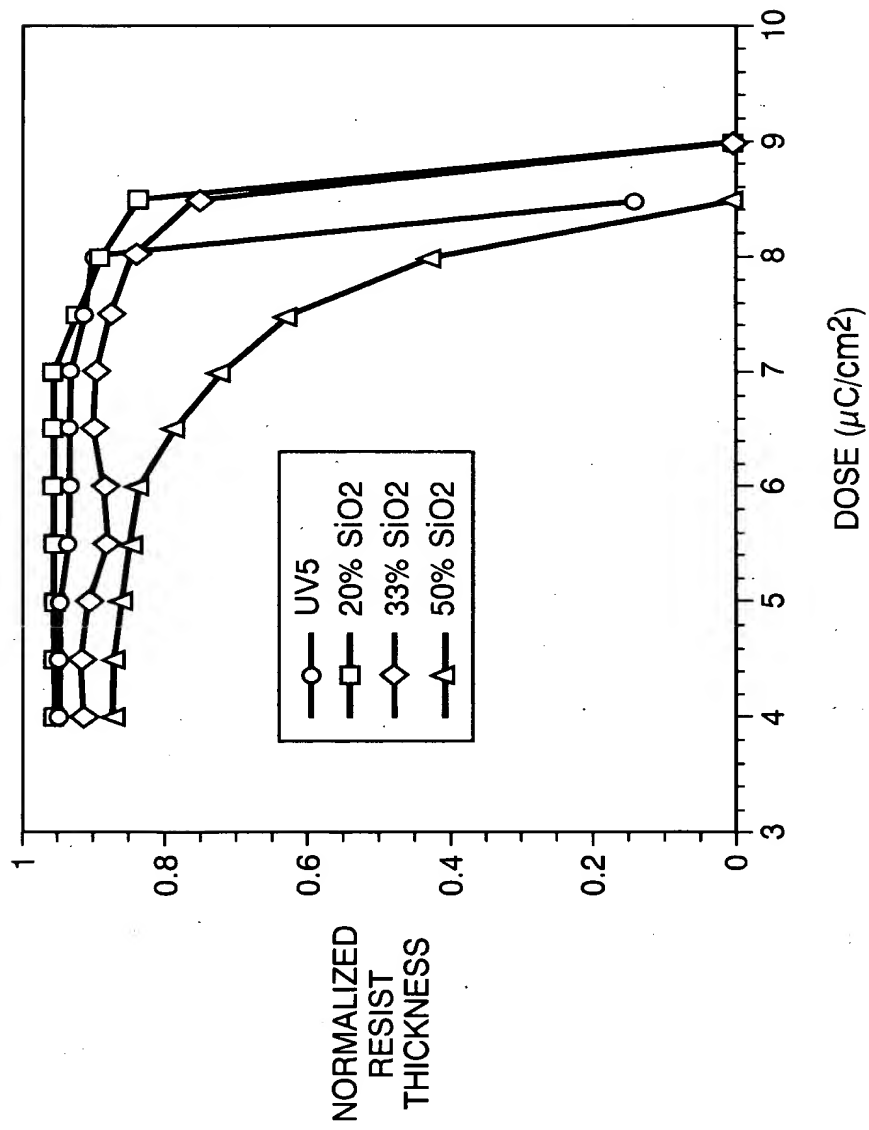
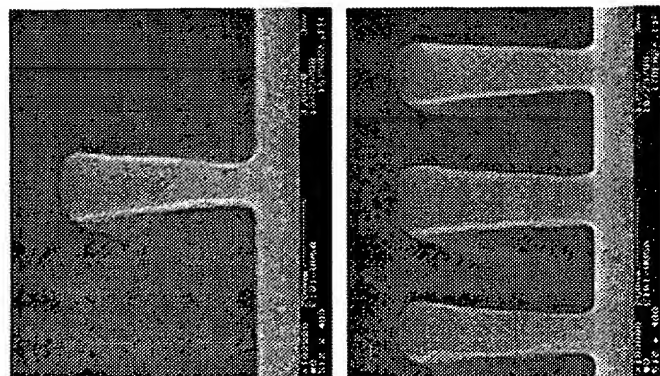
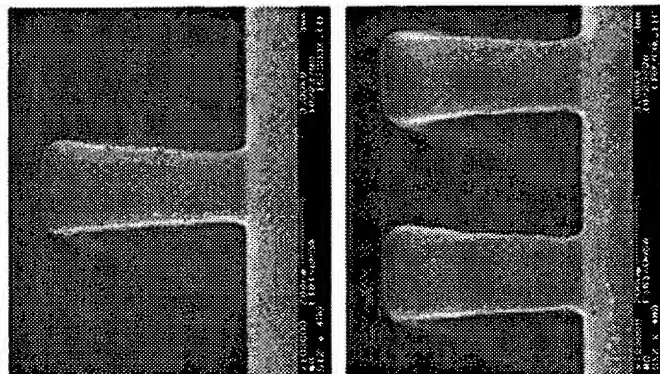


FIG. 1

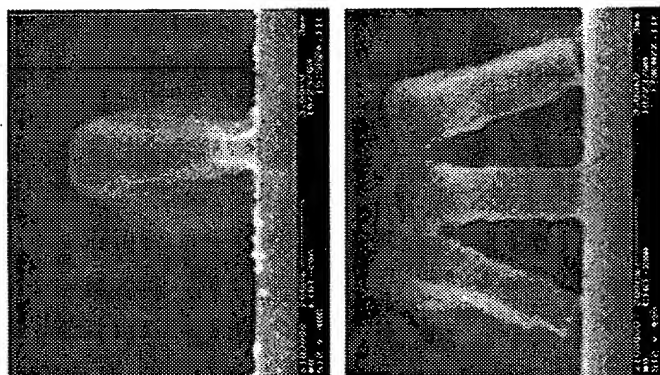
EXPERIMENTAL 20% SiO₂ EIRT RESIST



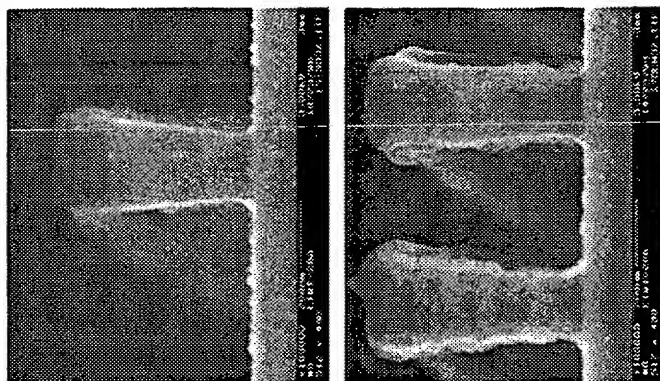
200 nm



300 nm



200 nm



300 nm

FIG. 2



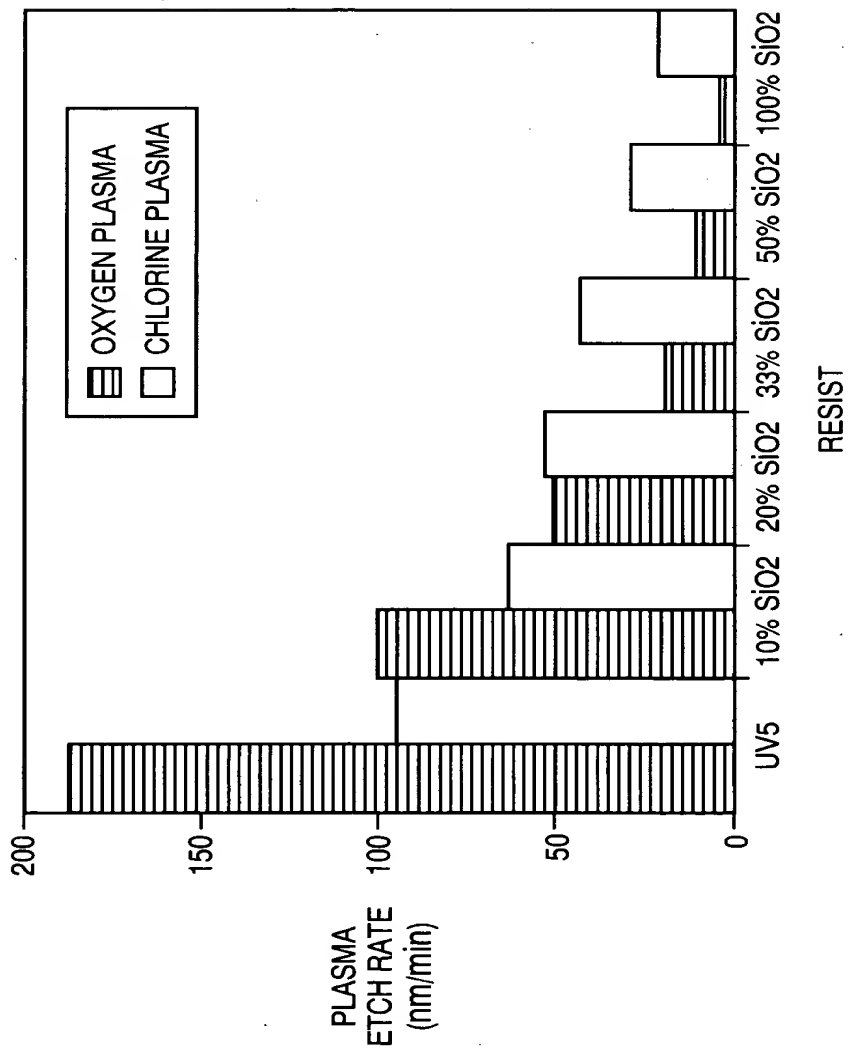


FIG. 3



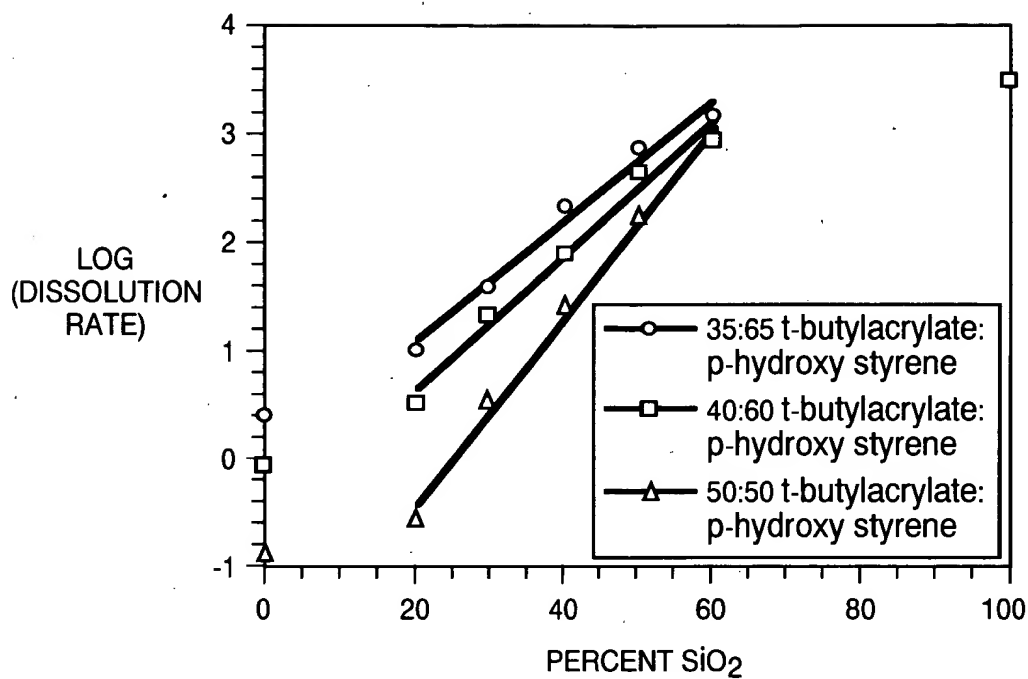


FIG. 4

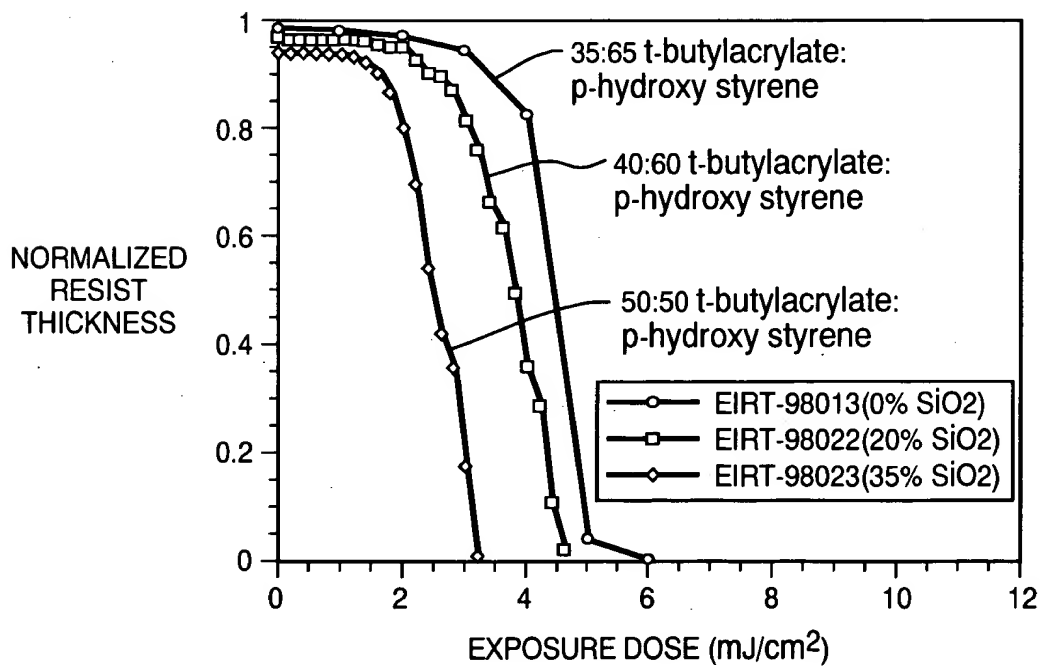
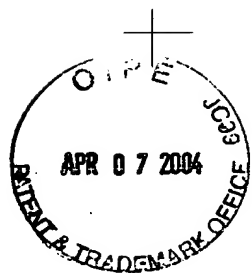
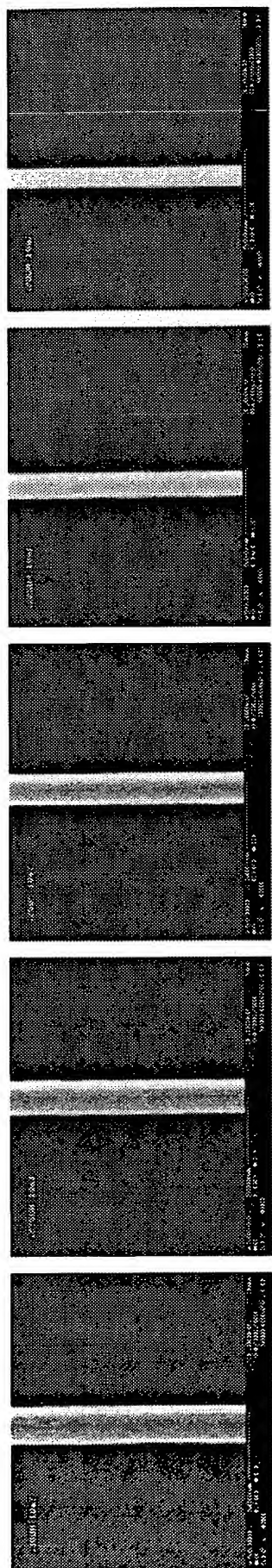
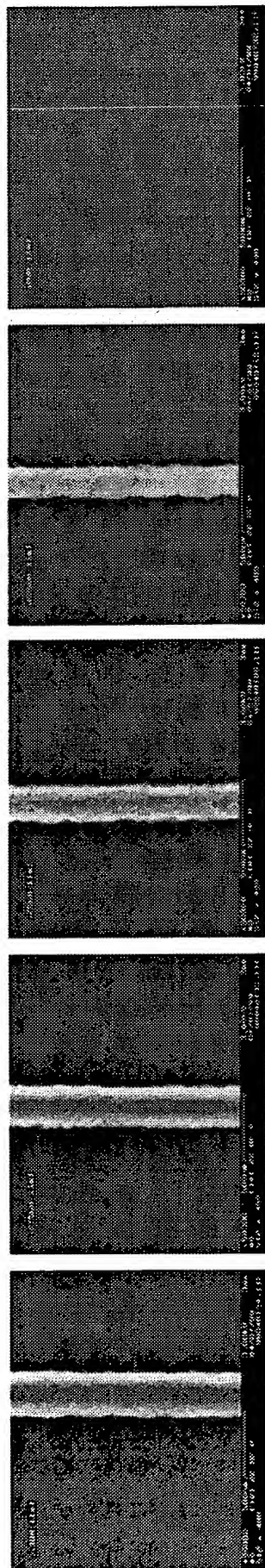


FIG. 5

EIRT 98013 RESIST (0% SiO₂) PREPARED FROM 35:65 T-BUTYLACRYLATE:P-HYDROXYSTYRENEEIRT 98022 RESIST (20% SiO₂) PREPARED FROM 40:60 T-BUTYLACRYLATE:P-HYDROXYSTYRENE

300 nm 275 nm 250 nm 225 nm 200 nm

FIG. 6